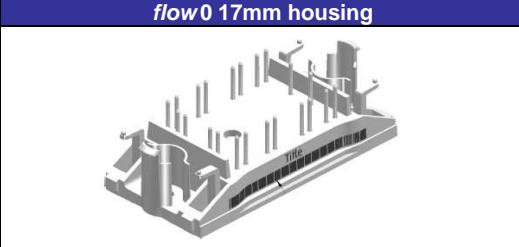
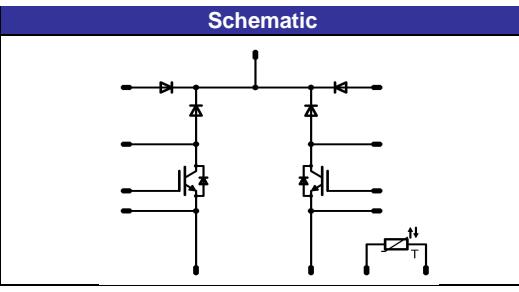


flowBOOST 0		1200V/40A
Features	<ul style="list-style-type: none"> • Ultra fast switching frequency • Low Inductance Layout • 1200V IGBT and 1200V SiC diode • Antiparallel IGBT protection diode with high current 	flow0 17mm housing 
Target Applications	• solar inverter	
Types	• V23990-P629-L99-PM	Schematic 

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
D7,D8				
Repetitive peak reverse voltage	V _{RRM}		1600	V
Forward average current	I _{FAV}	T _j =T _j max T _h =80°C T _c =80°C	45 45	A
Surge forward current	I _{FSM}		200	A
I ² t-value	I ² t	t _p =10ms T _j =150°C	200	A ² s
Power dissipation per Diode	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	68 102	W
Maximum Junction Temperature	T _j max		150	°C

T1,T2

Collector-emitter break down voltage	V _{CES}		1200	V
DC collector current	I _C	T _j =T _j max T _h =80°C T _c =80°C	55 55	A
Pulsed collector current	I _{Cpulse}	t _p limited by T _j max	160	A
Turn off safe operating area		T _j ≤150°C V _{CE} ≤=V _{CES}	160	A
Power dissipation per IGBT	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	202 306	W
Gate-emitter peak voltage	V _{GE}		25	V
Short circuit ratings	t _{SC} V _{CC}	T _j ≤150°C V _{GE} =15V	10 600	μs V
Maximum Junction Temperature	T _j max		150	°C

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
<hr/>				
D1,D2,D3,D4,D5,D6 *				
Peak Repetitive Reverse Voltage	V _{RRM}		1200	V
Forward average current	I _{FAV}	T _j =T _{jmax} T _c =80°C	54 55	A
Surge forward current	I _{FSM}	t _p =10ms	213	A
Repetitive peak forward current	I _{FRM}	t _p limited by T _{jmax}	141	A
Power dissipation per Diode	P _{tot}	T _j =T _{jmax} T _c =80°C	154 234	W
Maximum Junction Temperature	T _{jmax}		175	°C

* The values was measured on 3 diodes in parallel

D9,D10

Peak Repetitive Reverse Voltage	V _{RRM}	T _c =25°C	1200	V
Forward average current	I _{FAV}	T _j =T _{jmax} T _c =80°C	12 15	A
Surge non repetitive forward current	I _{FSM}	t _p =10ms half sine wave	28	A
Power dissipation per Diode	P _{tot}	T _j =T _{jmax} T _c =80°C	33 49	W
Maximum Junction Temperature	T _{jmax}		150	°C

Thermal Properties

Storage temperature	T _{stg}		-40...+125	°C
Operation temperature under switching condition	T _{op}		-40...+(T _{jmax} - 25)	°C

Insulation Properties

Insulation voltage		t=2s	DC voltage	4000	V
Creepage distance				min 12,7	mm
Clearance				min 12,7	mm

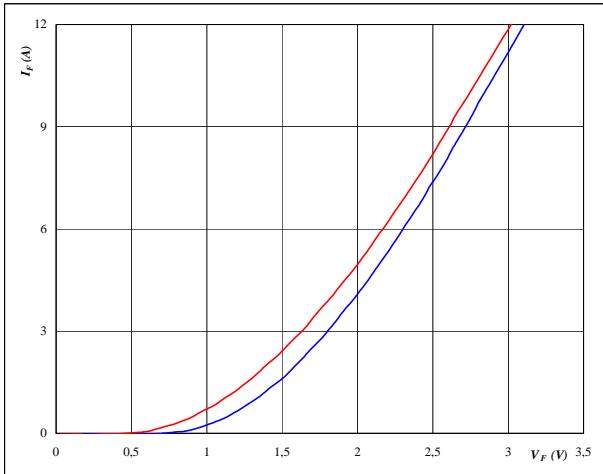
Characteristic Values

Parameter	Symbol	Conditions				Value			Unit
		V_{GE} [V] or V_{GS} [V]	V_r [V] or V_{CE} [V] or V_{DS} [V]	I_c [A] or I_F [A] or I_B [A]	T_J	Min	Typ	Max	
D7,D8									
Forward voltage	V_F			25	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	0,8	1,13 1,09	1,9	V
Threshold voltage (for power loss calc. only)	V_{IO}				$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$		0,93 0,80		V
Slope resistance (for power loss calc. only)	r_t				$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$		0,008 0,011		Ω
Reverse current	I_r		1500		$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$			0,05	mA
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal foil thickness=76um Kunze foil KU-AL F5					1,04		K/W
T1,T2									
Gate emitter threshold voltage	$V_{GE(\text{th})}$		15	0,00025	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	3,5	5,5	7,5	V
Collector-emitter saturation voltage	$V_{CE(\text{sat})}$		15	40	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	1	2,74 3,01	3,5	V
Collector-emitter cut-off	I_{CES}	0	1200		$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$			1	mA
Gate-emitter leakage current	I_{GES}		25		$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$			300	nA
Integrated Gate resistor	R_{gint}						none		Ω
Turn-on delay time	$t_{J(\text{on})}$	R _{off} =4 Ω R _{on} =4 Ω	15	700	40	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	23,2 22,6		
Rise time	t_r					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	10 11,2		ns
Turn-off delay time	$t_{d(\text{off})}$					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	186,4 215,8		
Fall time	t_f					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	11,1 32,3		
Turn-on energy loss per pulse	E_{on}					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	0,542 0,630		mWs
Turn-off energy loss per pulse	E_{off}					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	0,850 1,679		
Input capacitance	C_{iss}						3200		
Output capacitance	C_{oss}					$T_J=25^\circ\text{C}$	370		pF
Reverse transfer capacitance	C_{rss}						125		
Gate charge	Q_{Gate}	f=1MHz		30		$T_J=25^\circ\text{C}$	220	330	nC
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal foil thickness=76um Kunze foil KU-AL F5					0,35		K/W
D1,D2,D3,D4,D5,D6 *									
Forward voltage	V_F			30	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	1	1,49 1,77	1,9	V
Reverse leakage current	I_{rm}			700	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$			750	μA
Peak recovery current	I_{RRM}	R _{on} =4 Ω	15	700	40	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	29,24 28,42		
Reverse recovery time	t_{rr}					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	11,7 12,5		ns
Reverse recovery charge	Q_{rr}					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	0,187 0,19		μC
Reverse recovered energy	E_{rec}					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	0,026 0,028		mWs
Peak rate of fall of recovery current	$d(i_{\text{rec}})/dt$					$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$	7553 7097		A/ μs
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal foil thickness=76um Kunze foil KU-AL F5					0,62		K/W
D9,D10									
Diode forward voltage	V_F			4	$T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$		1,98 1,82		V
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal foil thickness=76um Kunze foil KU-AL F5					2,15		K/W
Thermistor									
Rated resistance	R				$T=25^\circ\text{C}$		21511		Ω
Deviation of R100	$\Delta R/R$	R100=1486 Ω			$T=100^\circ\text{C}$	-4,5		+4,5	%
Power dissipation	P				$T=25^\circ\text{C}$		210		mW
Power dissipation constant					$T=25^\circ\text{C}$		3,5		mW/K
B-value	$B(25/50)$				$T=25^\circ\text{C}$		3884		K
B-value	$B(25/100)$				$T=25^\circ\text{C}$		3964		K
Vincotech NTC Reference								F	

D9,D10
Figure 25

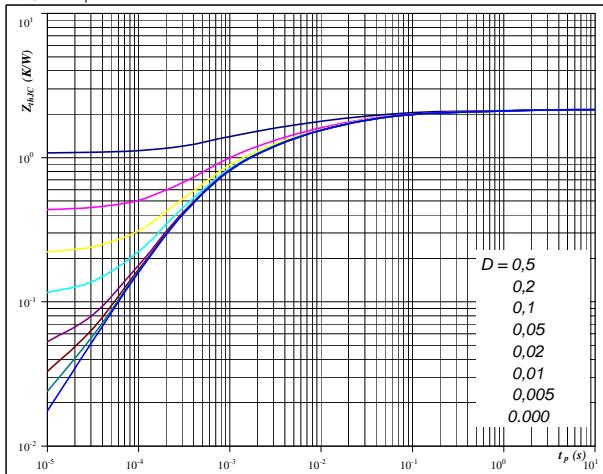
Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$


D9,D10
Figure 26

Diode transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$

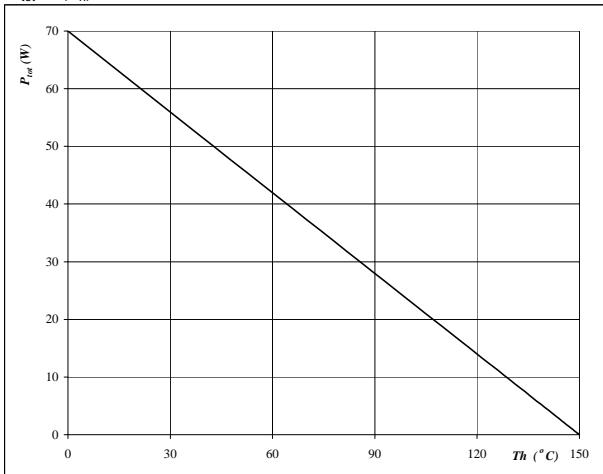

At

$$t_p = 250 \text{ } \mu\text{s} \quad T_j = 25/125 \text{ } ^\circ\text{C}$$

D9,D10
Figure 27

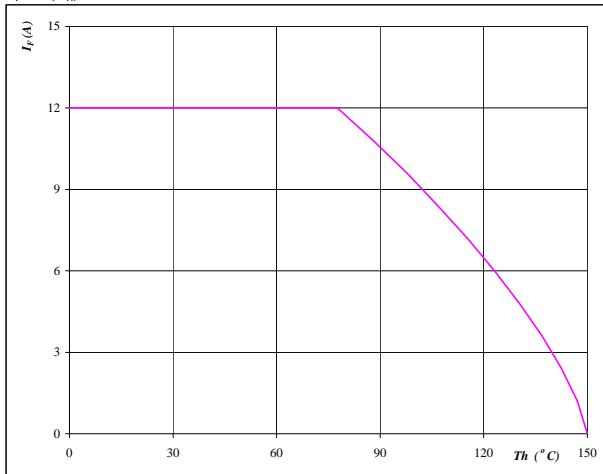
Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$


D9,D10
Figure 28

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$

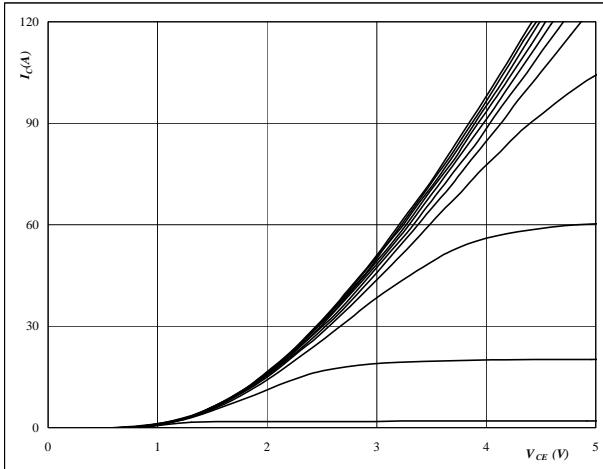

At

$$T_j = 150 \text{ } ^\circ\text{C}$$

D9,D10

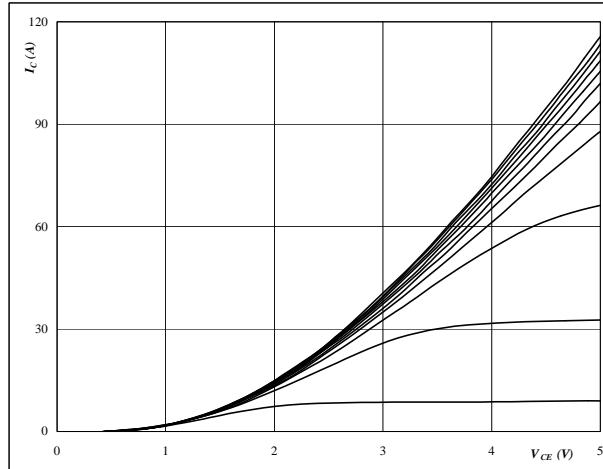
T1/(D1,D2,D3) , T2/(D4,D5,D6)

Figure 1
Typical output characteristics
 $I_D = f(V_{DS})$



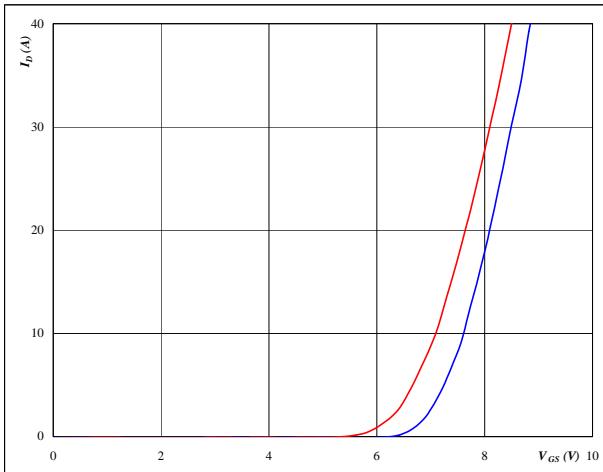
At
 $t_p = 250 \mu\text{s}$
 $T_j = 25^\circ\text{C}$
 V_{GS} from 7 V to 17 V in steps of 1 V

Figure 2
Typical output characteristics
 $I_D = f(V_{DS})$



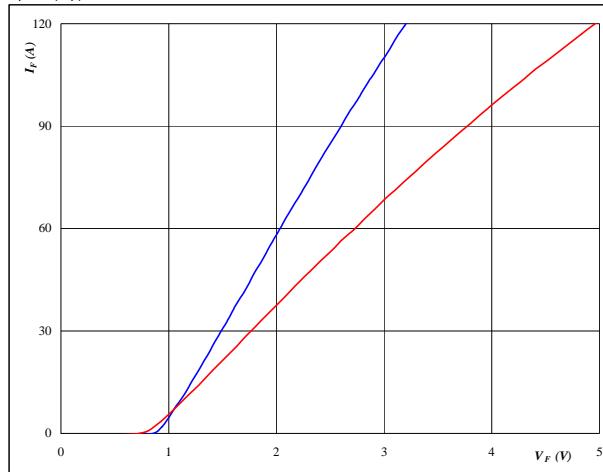
At
 $t_p = 250 \mu\text{s}$
 $T_j = 126^\circ\text{C}$
 V_{GS} from 7 V to 17 V in steps of 1 V

Figure 3
Typical transfer characteristics
 $I_D = f(V_{GS})$



At
 $t_p = 100 \mu\text{s}$
 $V_{DS} = 10 \text{ V}$
 $T_j = 25/125^\circ\text{C}$

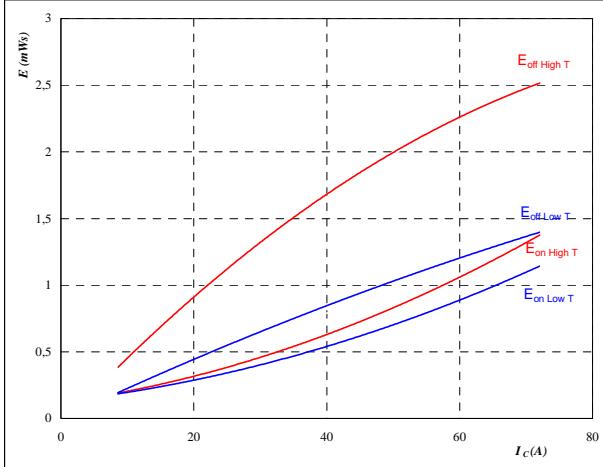
Figure 4
Typical diode forward current as a function of forward voltage
 $I_F = f(V_F)$



At
 $t_p = 250 \mu\text{s}$
 $T_j = 25/125^\circ\text{C}$

T1/(D1,D2,D3) , T2/(D4,D5,D6)

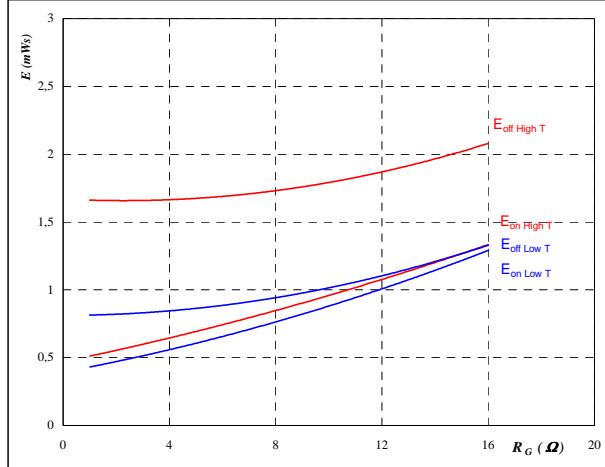
Figure 5
Typical switching energy losses
as a function of collector current
 $E = f(I_D)$



With an inductive load at

$T_j = 25/125$ °C
 $V_{DS} = 700$ V
 $V_{GS} = 15$ V
 $R_{gon} = 4$ Ω
 $R_{goff} = 4$ Ω

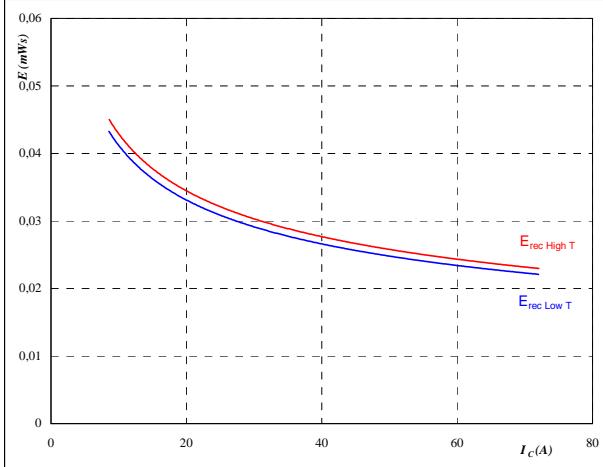
Figure 6
Typical switching energy losses
as a function of gate resistor
 $E = f(R_G)$



With an inductive load at

$T_j = 25/125$ °C
 $V_{DS} = 700$ V
 $V_{GS} = 15$ V
 $I_D = 40$ A

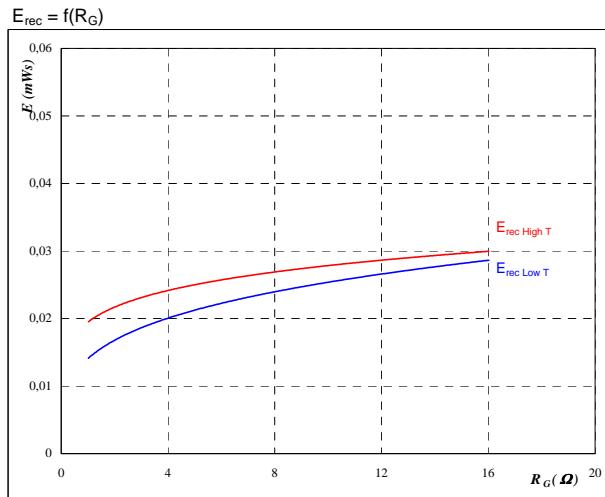
Figure 7
Typical reverse recovery energy loss
as a function of collector (drain) current
 $E_{rec} = f(I_c)$



With an inductive load at

$T_j = 25/125$ °C
 $V_{DS} = 700$ V
 $V_{GS} = 15$ V
 $R_{gon} = 4$ Ω
 $R_{goff} = 4$ Ω

Figure 8
Typical reverse recovery energy loss
as a function of gate resistor

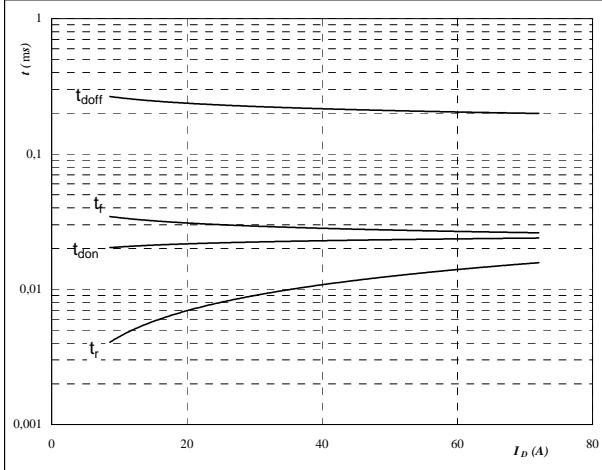


With an inductive load at

$T_j = 25/125$ °C
 $V_{DS} = 700$ V
 $V_{GS} = 15$ V
 $I_D = 40$ A

T1/(D1,D2,D3) , T2/(D4,D5,D6)

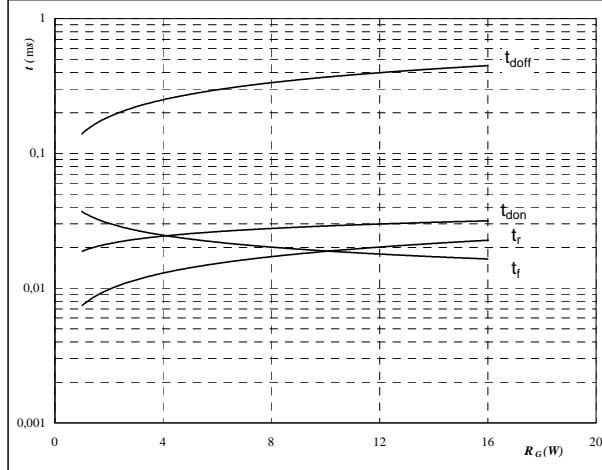
Figure 9
Typical switching times as a function of collector current
 $t = f(I_D)$



With an inductive load at

$T_j = 125 \text{ } ^\circ\text{C}$
 $V_{DS} = 700 \text{ V}$
 $V_{GS} = 15 \text{ V}$
 $R_{gon} = 4 \Omega$
 $R_{goff} = 4 \Omega$

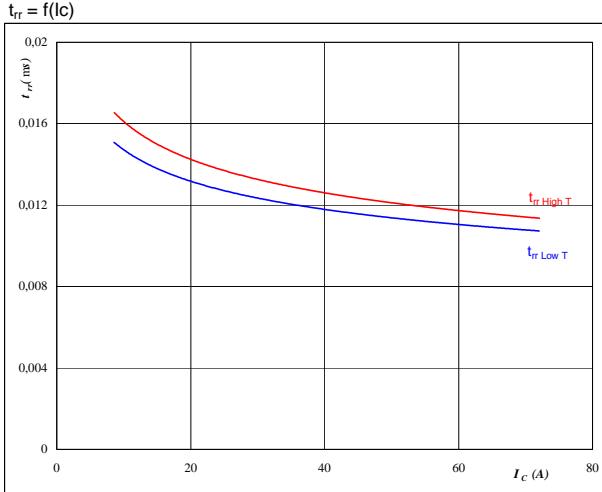
Figure 10
Typical switching times as a function of gate resistor
 $t = f(R_G)$



With an inductive load at

$T_j = 125 \text{ } ^\circ\text{C}$
 $V_{DS} = 700 \text{ V}$
 $V_{GS} = 15 \text{ V}$
 $I_C = 40 \text{ A}$

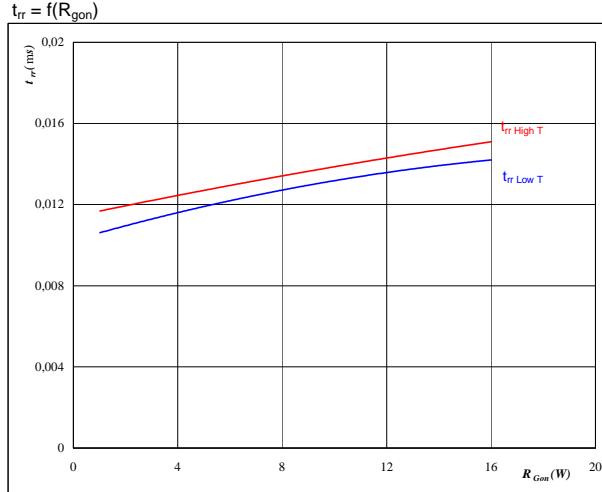
Figure 11
Typical reverse recovery time as a function of collector current



At

$T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 700 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $R_{gon} = 4 \Omega$

Figure 12
Typical reverse recovery time as a function of IGBT turn on gate resistor



At

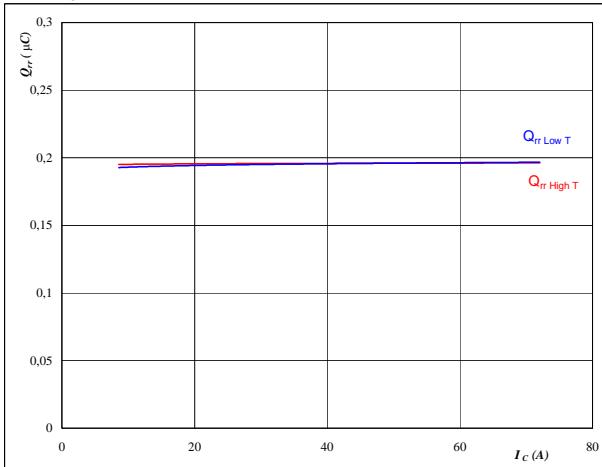
$T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 700 \text{ V}$
 $I_f = 40 \text{ A}$
 $V_{GS} = 15 \text{ V}$

T1/(D1,D2,D3) , T2/(D4,D5,D6)

Figure 13

D1,D2,D3,D4,D5,D6

Typical reverse recovery charge as a function of collector current
 $Q_{rr} = f(I_C)$

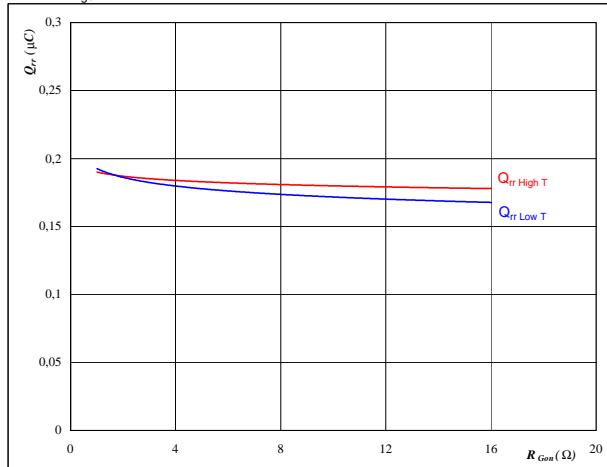

At

$T_j = \textcolor{blue}{25}/\textcolor{red}{125} \quad ^\circ\text{C}$
 $V_{CE} = 700 \quad \text{V}$
 $V_{GE} = 15 \quad \text{V}$
 $R_{gon} = 4 \quad \Omega$

Figure 14

D1,D2,D3,D4,D5,D6

Typical reverse recovery charge as a function of IGBT turn on gate resistor
 $Q_{rr} = f(R_{gon})$

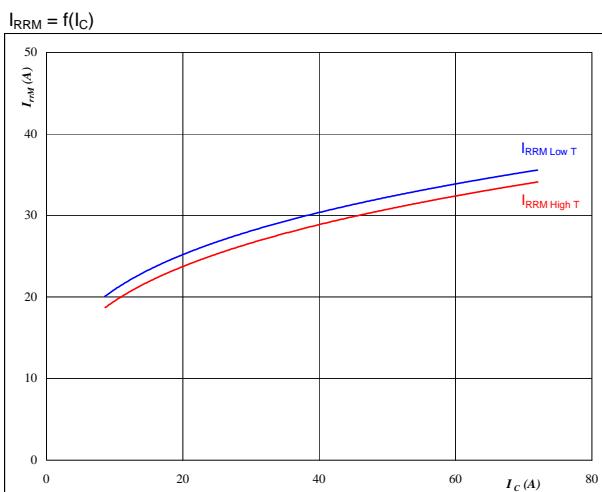

At

$T_j = \textcolor{blue}{25}/\textcolor{red}{125} \quad ^\circ\text{C}$
 $V_R = 700 \quad \text{V}$
 $I_F = 40 \quad \text{A}$
 $V_{GS} = 15 \quad \text{V}$

Figure 15

D1,D2,D3,D4,D5,D6

Typical reverse recovery current as a function of collector current
 $I_{RRM} = f(I_C)$

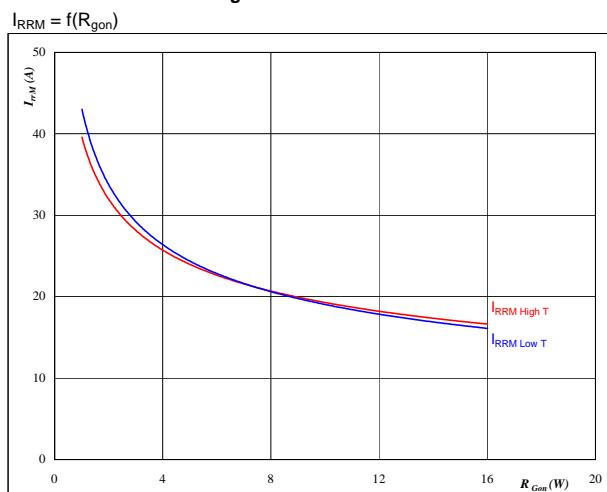

At

$T_j = \textcolor{blue}{25}/\textcolor{red}{125} \quad ^\circ\text{C}$
 $V_{CE} = 700 \quad \text{V}$
 $V_{GE} = 15 \quad \text{V}$
 $R_{gon} = 4 \quad \Omega$

Figure 16

D1,D2,D3,D4,D5,D6

Typical reverse recovery current as a function of IGBT turn on gate resistor
 $I_{RRM} = f(R_{gon})$

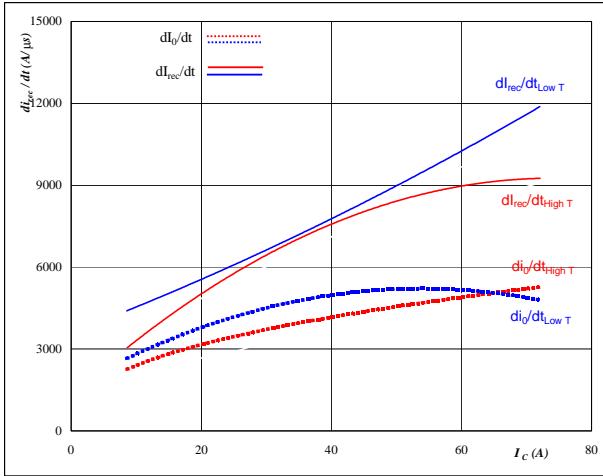

At

$T_j = \textcolor{blue}{25}/\textcolor{red}{125} \quad ^\circ\text{C}$
 $V_R = 700 \quad \text{V}$
 $I_F = 40 \quad \text{A}$
 $V_{GS} = 15 \quad \text{V}$

T1/(D1,D2,D3) , T2/(D4,D5,D6)

Figure 17

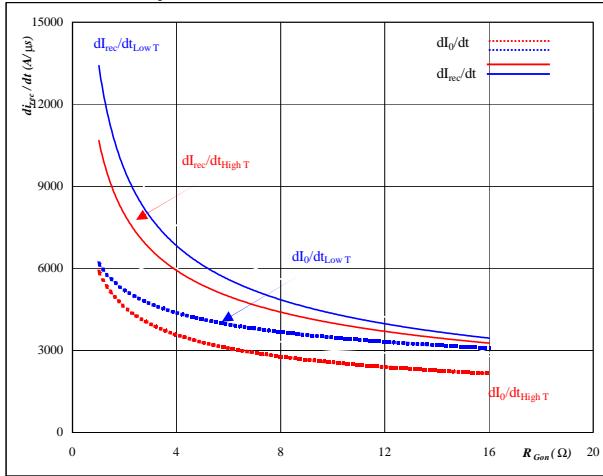
Typical rate of fall of forward
and reverse recovery current as a
function of collector current
 $dI_0/dt, dI_{rec}/dt = f(I_C)$


At

$T_j = 25/125$ °C
 $V_{CE} = 700$ V
 $V_{GE} = 15$ V
 $R_{gon} = 4$ Ω

D1,D2,D3,D4,D5,D6
Figure 18

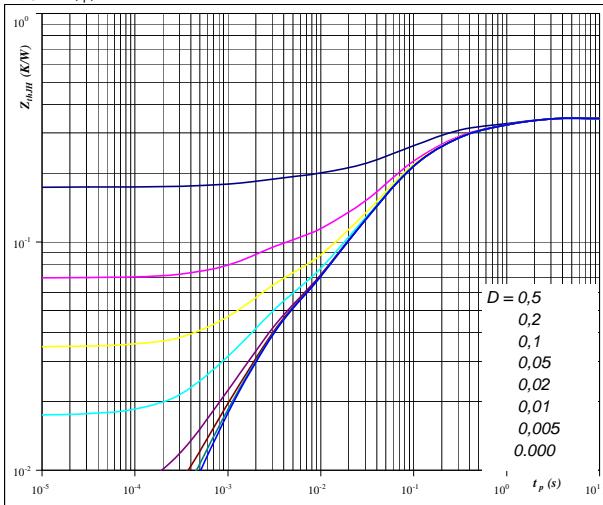
Typical rate of fall of forward
and reverse recovery current as a
function of IGBT turn on gate resistor
 $dI_0/dt, dI_{rec}/dt = f(R_{gon})$


At

$T_j = 25/125$ °C
 $V_R = 700$ V
 $I_F = 40$ A
 $V_{GS} = 15$ V

Figure 19
T1,T2

IGBT transient thermal impedance
as a function of pulse width

 $Z_{thJH} = f(t_p)$

At

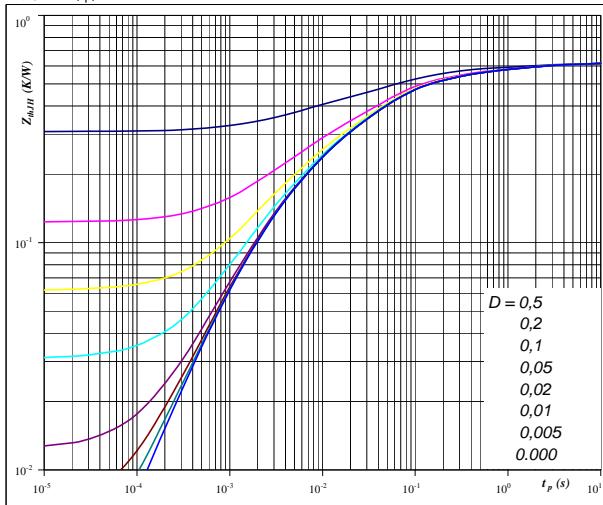
$D = t_p / T$
 $R_{thJH} = 0.35$ K/W

IGBT thermal model values

R (C/W)	Tau (s)
0,080	0,780
0,161	0,100
0,072	0,030
0,035	0,002

Figure 20
D1,D2,D3,D4,D5,D6

FWD transient thermal impedance
as a function of pulse width

 $Z_{thJH} = f(t_p)$

At

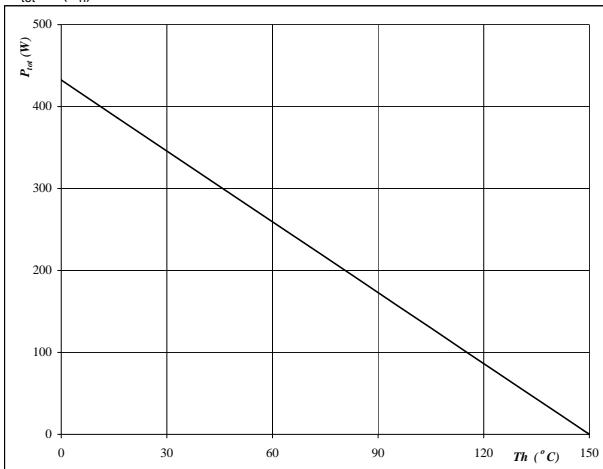
$D = t_p / T$
 $R_{thJH} = 0,62$ K/W

FWD thermal model values

R (C/W)	Tau (s)
0,042	2,693
0,072	0,483
0,218	0,064
0,128	0,017
0,125	0,004

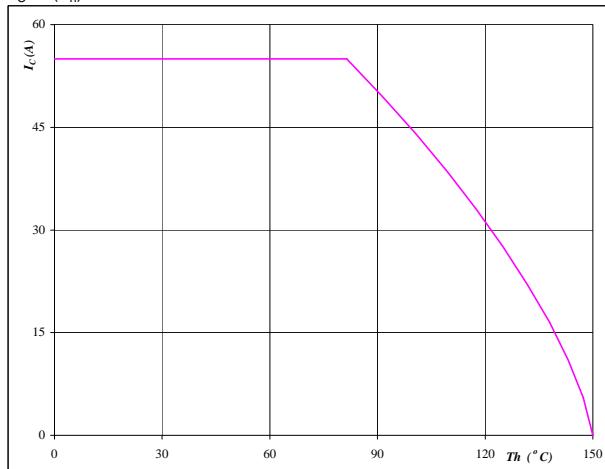
T1/(D1,D2,D3) , T2/(D4,D5,D6)

Figure 21
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$



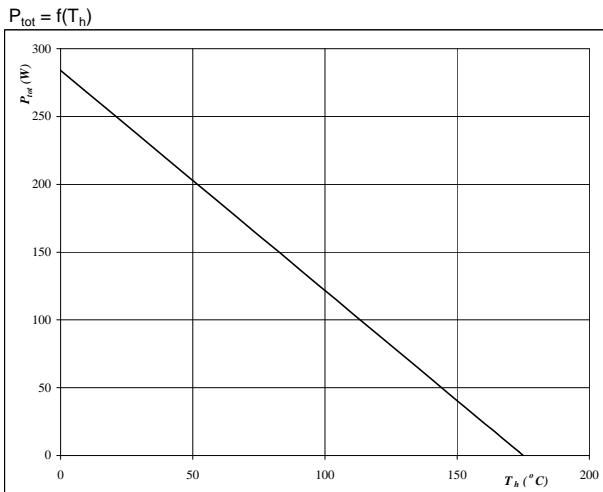
At
 $T_j = 150 \text{ } ^\circ\text{C}$

Figure 22
Collector/Drain current as a function of heatsink temperature
 $I_C = f(T_h)$



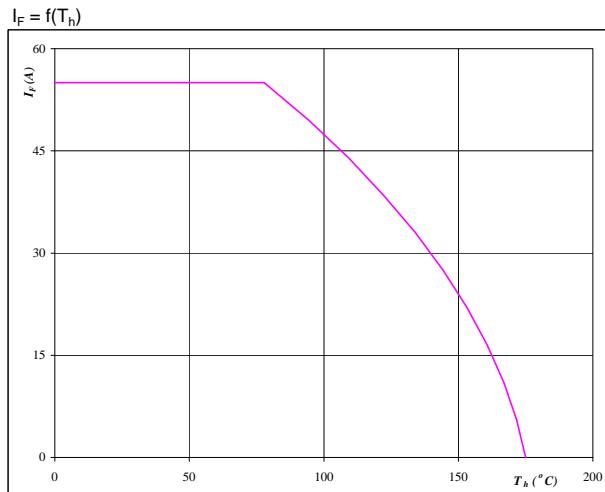
At
 $T_j = 150 \text{ } ^\circ\text{C}$
 $V_{GS} = 15 \text{ V}$

Figure 23
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$



At
 $T_j = 175 \text{ } ^\circ\text{C}$

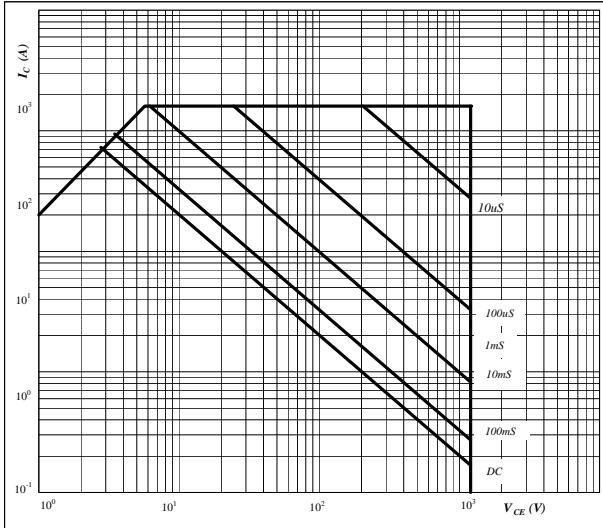
Figure 24
Forward current as a function of heatsink temperature
 $I_F = f(T_h)$



At
 $T_j = 175 \text{ } ^\circ\text{C}$

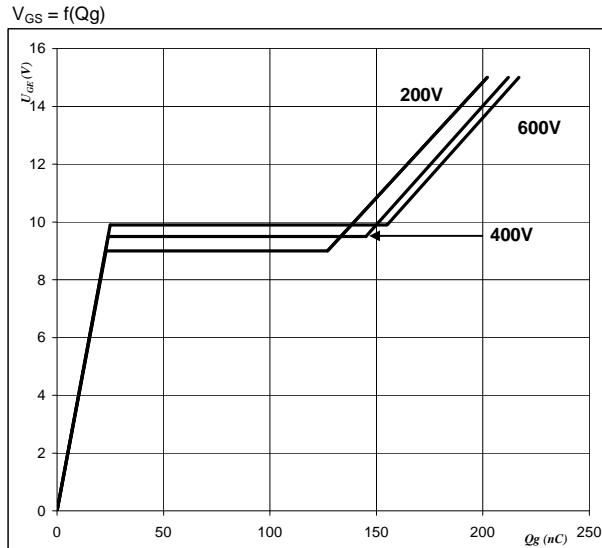
T1/(D1,D2,D3) , T2/(D4,D5,D6)

Figure 25
**Safe operating area as a function
of drain-source voltage**
 $I_D = f(V_{DS})$



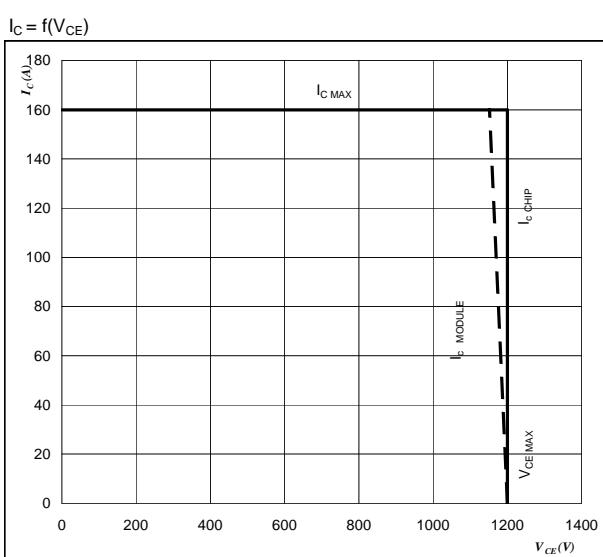
At
D = single pulse
 $T_h = 80^\circ\text{C}$
 $V_{GE} = 15\text{ V}$
 $T_j = T_{jmax}^\circ\text{C}$

Figure 26
Gate voltage vs Gate charge
 $V_{GS} = f(Qg)$



At
 $I_C = 40\text{ A}$

Figure 29
Reverse bias safe operating area

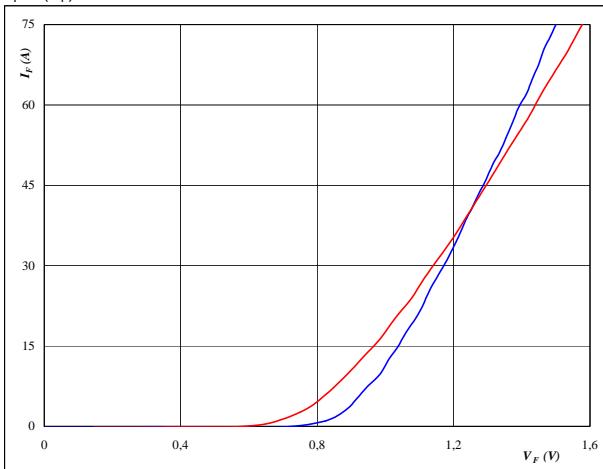


At
 $T_{vj} = 150^\circ\text{C}$

D7,D8
Figure 1

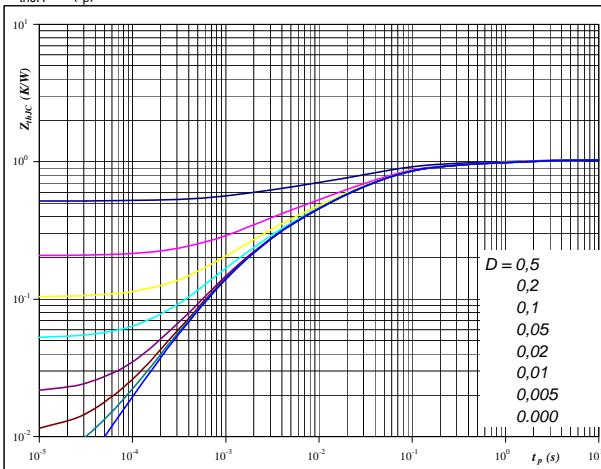
Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$


D7,D8
Figure 2

Diode transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$


At

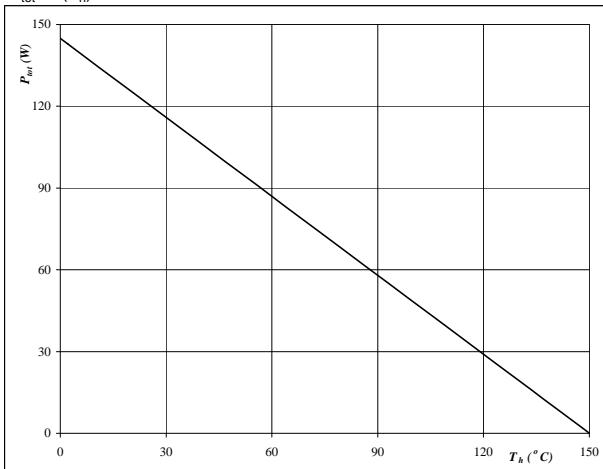
$$T_j = \frac{25}{125} \quad {}^\circ\text{C}$$

$$t_p = 250 \quad \mu\text{s}$$

D7,D8
Figure 3

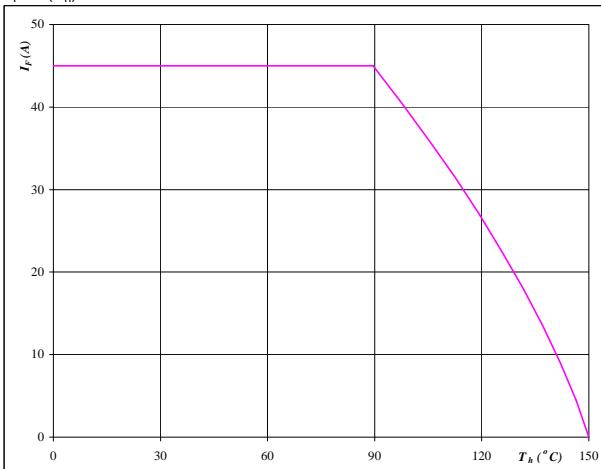
Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$


D7,D8
Figure 4

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$


At

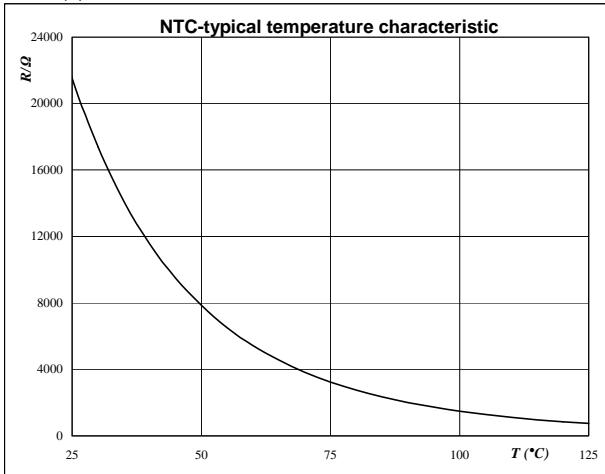
$$T_j = 150 \quad {}^\circ\text{C}$$

D7,D8

Thermistor

Figure 1 Thermistor

Typical NTC characteristic
as a function of temperature
 $R_T = f(T)$

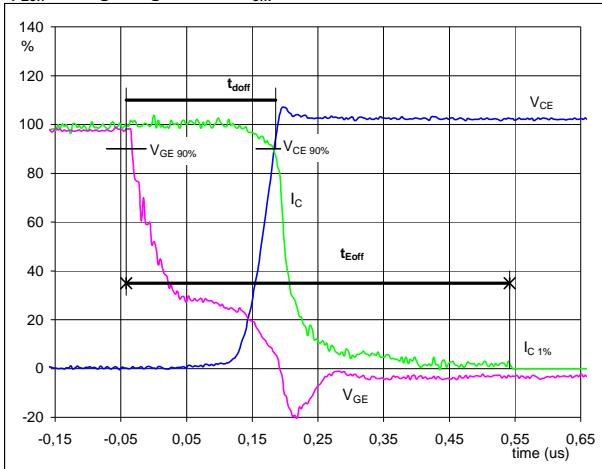


Switching Definitions Boost

General conditions

T_j	= 125 °C
R_{gon}	= 4 Ω
R_{goff}	= 4 Ω

Figure 1
IGBT
Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}

(t_{Eoff} = integrating time for E_{off})


$$V_{GE}(0\%) = 0 \text{ V}$$

$$V_{GE}(100\%) = 15 \text{ V}$$

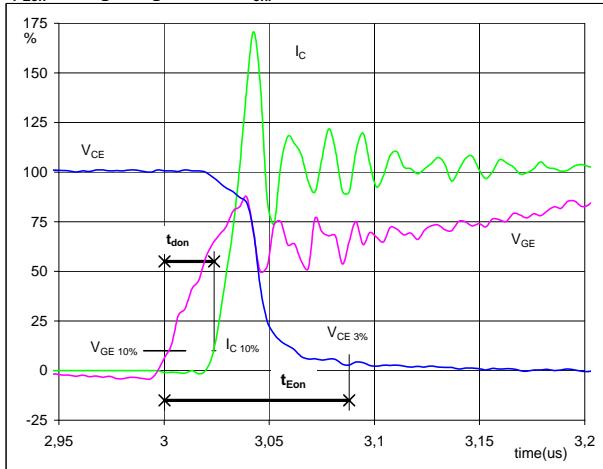
$$V_C(100\%) = 700 \text{ V}$$

$$I_C(100\%) = 40 \text{ A}$$

$$t_{doff} = 0,216 \mu\text{s}$$

$$t_{Eoff} = 0,583 \mu\text{s}$$

Figure 2
IGBT
Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}

(t_{Eon} = integrating time for E_{on})


$$V_{GE}(0\%) = 0 \text{ V}$$

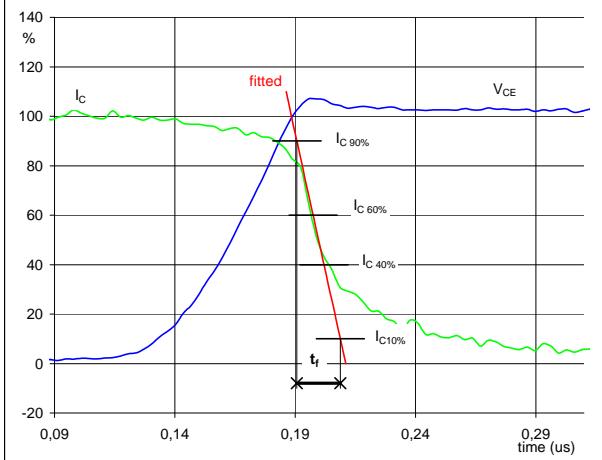
$$V_{GE}(100\%) = 15 \text{ V}$$

$$V_C(100\%) = 700 \text{ V}$$

$$I_C(100\%) = 40 \text{ A}$$

$$t_{don} = 0,023 \mu\text{s}$$

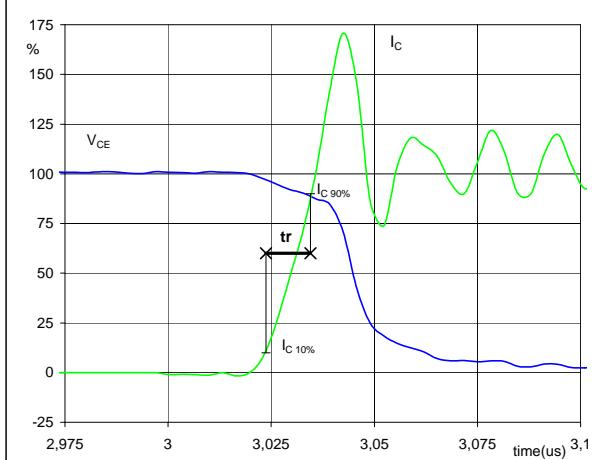
$$t_{Eon} = 0,088 \mu\text{s}$$

Figure 3
IGBT
Turn-off Switching Waveforms & definition of t_f


$$V_C(100\%) = 700 \text{ V}$$

$$I_C(100\%) = 40 \text{ A}$$

$$t_f = 0,032 \mu\text{s}$$

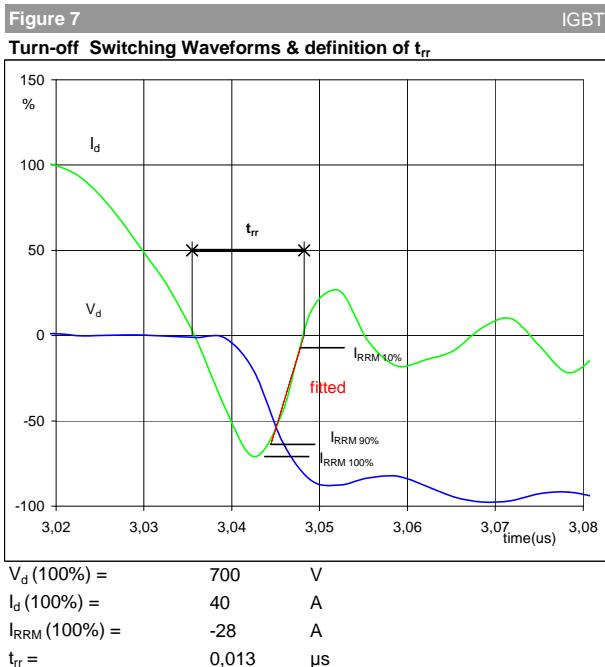
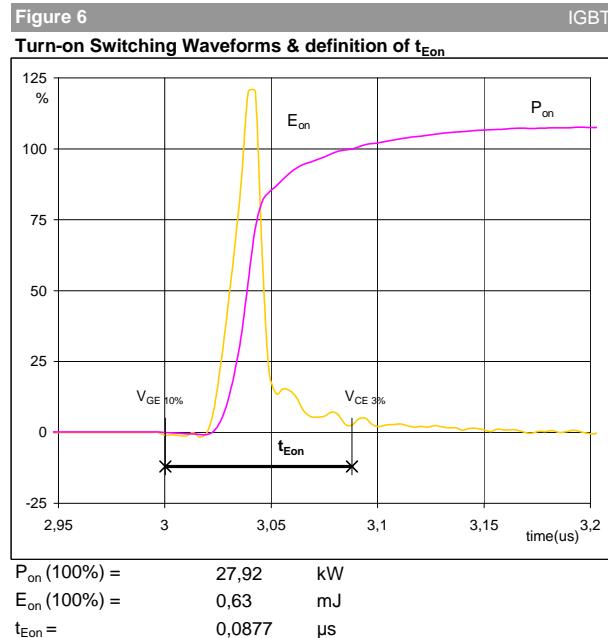
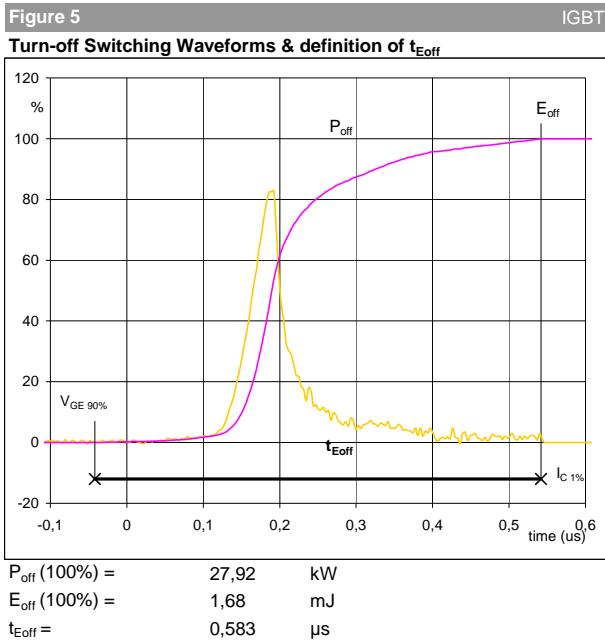
Figure 4
IGBT
Turn-on Switching Waveforms & definition of t_r


$$V_C(100\%) = 700 \text{ V}$$

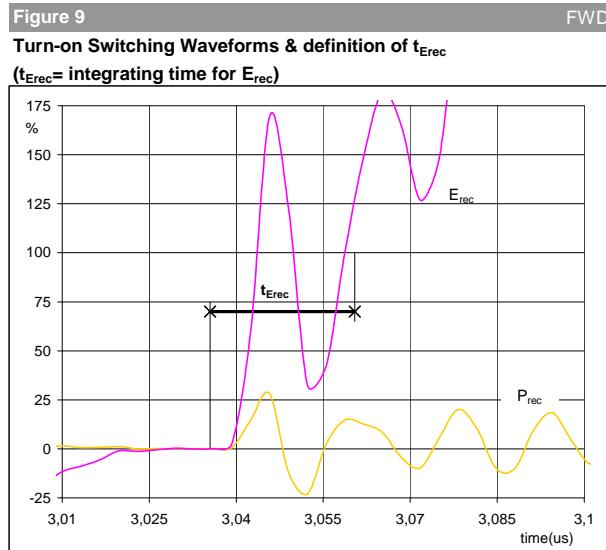
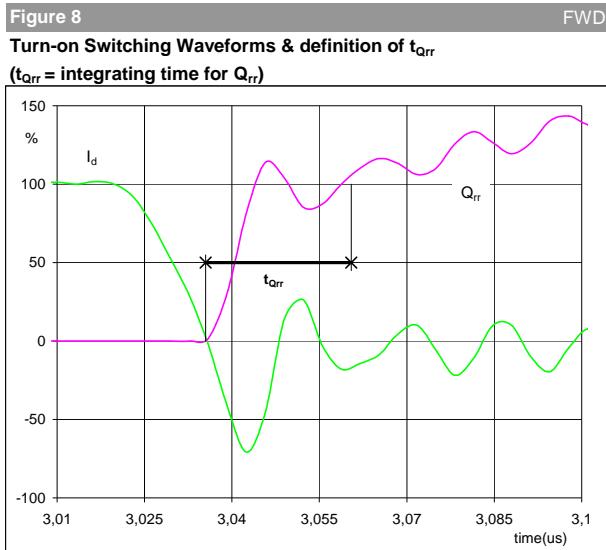
$$I_C(100\%) = 40 \text{ A}$$

$$t_r = 0,011 \mu\text{s}$$

Switching Definitions Boost



Switching Definitions Boost



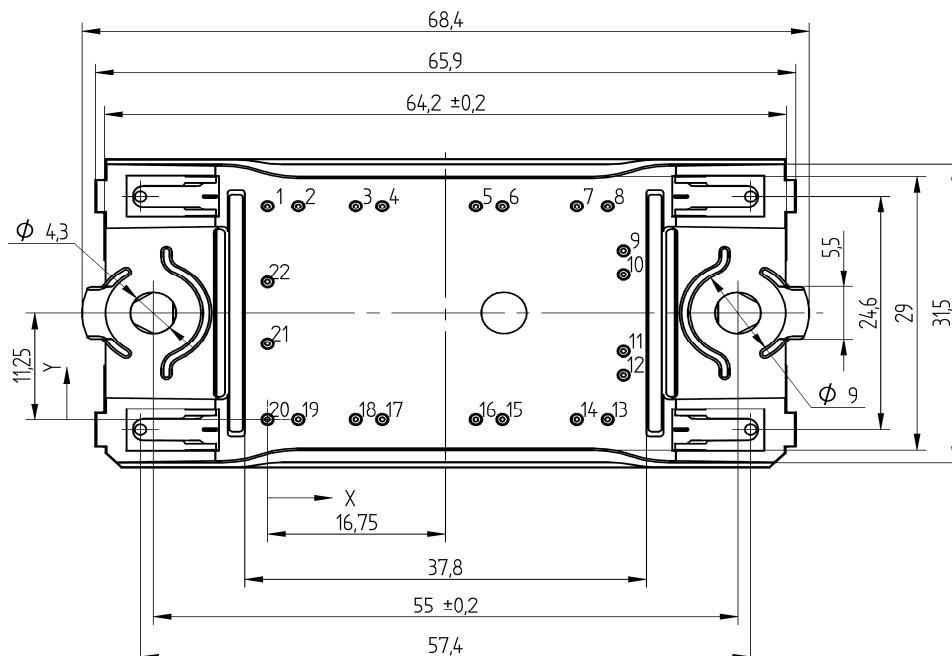
Ordering Code and Marking - Outline - Pinout

Ordering Code & Marking

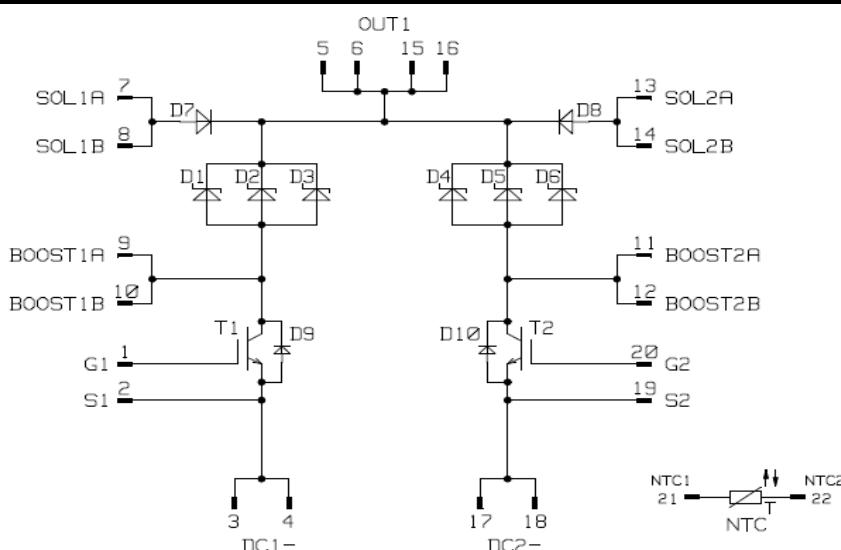
Version	Ordering Code	in DataMatrix as	in packaging barcode as
without thermal paste 17mm housing	V23990-P629-L99-PM	P629-L99	P629-L99

Outline

Pin Table		
Pin	X	Y
1	0	22,5
2	2,9	22,5
3	8,3	22,5
4	10,8	22,5
5	19,6	22,5
6	22,1	22,5
7	29,1	22,5
8	32	22,5
9	33,5	17,8
10	33,5	15,3
11	33,5	7,2
12	33,5	4,7
13	32	0
14	29,1	0
15	22,1	0
16	19,6	0
17	10,8	0
18	8,3	0
19	2,9	0
20	0	0
21	0	8
22	0	14,5



Pinout



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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.